Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/821,859	CHANG, DEUK-HWAN
Examiner	Art Unit
Kaitlin S. Joerger	3653

SEARCHED					
Class	Subclass	Date	Examiner		
271	104,112	5/11/06	nm		
-					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated Search	10/27/06	1	
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